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Surface chemical analysis - X-ray photoelectron spectroscopy - Procedures for determining backgrounds

Contents		Page
Foreword		iv
Introduction		v
1	Scope	1
2	Terms and definitions	1
3	Symbols and abbreviated terms	1
4	Types of background in XPS	1
5	Removal of X-ray satellites from electron spectra	2
6	Estimation and removal of inelastic electron scattering from electron spectra	2
6.1	General Information	2
6.2	Procedures to account for inelastic electron scattering	2
6.2.1	Introduction	2
6.2.2	Estimation of the linear background and its removal	3
6.2.3	Integral background removal	3
6.2.4	Removal based on the electron inelastic-scattering cross-section	4
6.3	Procedures accounting for both inelastic and elastic scattering	5
6.4	Less commonly used procedures	5
6.5	Role of surface and core-hole effects in background determination	6
6.6	Determining the background for inhomogeneous materials	6
7	Comparisons of procedures for removing effects of inelastic electron scattering from electron spectra	7
Bibliography		8